



### 30V P-CHANNEL ENHANCEMENT MODE MOSFET PowerDI5060-8

## **Product Summary**

BV <sub>DSS</sub>	R <sub>DS(ON)</sub>	I <sub>D</sub> T <sub>C</sub> = +25°C
-30V	$3.8$ m $\Omega$ @ $V_{GS} = -10$ V	-135A
	6.0mΩ @ V <sub>GS</sub> = -5V	-110A

# **Description**

This new generation MOSFET is designed to minimize RDS(ON) and yet maintain superior switching performance. This device is ideal for use in notebook battery power management and load switch.

PowerDI5060-8

# Applications

Switch

#### **Features**

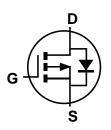
- 100% Unclamped Inductive Switch (UIS) Test in Production
- Thermally Efficient Package-Cooler Running Applications
- High Conversion Efficiency
- Low R<sub>DS(ON)</sub> Minimizes On State Losses
- <1.1mm Package Profile Ideal for Thin Applications
- Lead-Free Finish; RoHS Compliant (Notes 1 & 2)
- Halogen and Antimony Free. "Green" Device (Note 3)

### Mechanical Data

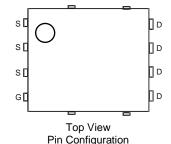
- Case: PowerDI<sup>®</sup>5060-8
- Case Material: Molded Plastic, "Green" Molding Compound; UL Flammability Classification Rating 94V-0
- Moisture Sensitivity: Level 1 per J-STD-020
- Terminal Finish Matte Tin Annealed over Copper Leadframe; Solderable per MIL-STD-202, Method 208@3
- Weight: 0.097 grams (Approximate)







Internal Schematic



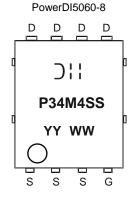
Ordering Information (Note 4)

Part Number	Case	Packaging
DMP34M4SPS-13	PowerDI5060-8	2,500 / Tape & Reel

Notes:

- 1. EU Directive 2002/95/EC (RoHS) & 2011/65/EU (RoHS 2) compliant. All applicable RoHS exemptions applied.
- 2. See http://www.diodes.com/quality/lead\_free.html for more information about Diodes Incorporated's definitions of Halogen- and Antimony-free, "Green" and Lead-free.
- 3. Halogen- and Antimony-free "Green" products are defined as those which contain <900ppm bromine, <900ppm chlorine (<1500ppm total Br + CI) and
- 4. For packaging details, go to our website at https://www.diodes.com/design/support/packaging/diodes-packaging/.

### **Marking Information**



P34M4SS = Product Type Marking Code YYWW = Date Code Marking YY = Last Two Digits of Year (ex: 17 = 2017) WW = Week Code (01 to 53)



# **Maximum Ratings** (@T<sub>A</sub> = +25°C, unless otherwise specified.)

Characteristic	Symbol	Value	Unit	
Drain-Source Voltage	V <sub>DSS</sub>	-30	V	
Gate-Source Voltage		V <sub>GSS</sub>	±25	V
Continuous Drain Current, $V_{GS} = -10V$ (Note 7) $ T_C = +25^{\circ}C $ $ T_C = +70^{\circ}C $		I <sub>D</sub>	-135 -110	А
Pulsed Drain Current (380µs Pulse, Duty Cycle = 1%)	I <sub>DM</sub>	-350	Α	
Maximum Continuous Body Diode Forward Current (Note 6)	Is	-2.9	Α	
Pulsed Body Diode Forward Current (380µs Pulse, Duty Cycle =	I <sub>SM</sub>	-350	Α	
Avalanche Current, L = 0.1mH (Note 8)		I <sub>AS</sub>	-60	Α
Avalanche Energy, L = 0.1mH (Note 8)		E <sub>AS</sub>	180	mJ

## **Thermal Characteristics**

Characteristic		Symbol	Value	Unit
Total Power Dissipation (Note 5)		$P_{D}$	1.5	W
Thermal Resistance, Junction to Ambient (Note 5)	Steady State	$R_{\theta JA}$	94	°C/W
Total Power Dissipation (Note 6)		P <sub>D</sub>	3.0	W
Thermal Resistance, Junction to Ambient (Note 6)	Steady State	$R_{\theta JA}$	47	°C/W
Total Power Dissipation (Note 7)		P <sub>D</sub>	100	W
Thermal Resistance, Junction to Case (Note 7)		$R_{\theta JC}$	1.4	°C/W
Operating and Storage Temperature Range		T <sub>J,</sub> T <sub>STG</sub>	-55 to +150	°C

# **Electrical Characteristics** (@T<sub>A</sub> = +25°C, unless otherwise specified.)

Characteristic	Symbol	Min	Тур	Max	Unit	Test Condition	
OFF CHARACTERISTICS (Note 9)							
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	-30	_	_	V	$V_{GS} = 0V, I_D = -250\mu A$	
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	_	_	-1	μΑ	$V_{DS} = -24V, V_{GS} = 0V$	
Gate-Source Leakage	I <sub>GSS</sub>	_	_	±100	nA	$V_{GS} = \pm 20V, V_{DS} = 0V$	
ON CHARACTERISTICS (Note 9)						•	
Gate Threshold Voltage	V <sub>GS(TH)</sub>	-1.6		-2.6	V	$V_{DS} = V_{GS}, I_{D} = -250 \mu A$	
Static Drain-Source On-Resistance		_	2.9	3.8	mΩ	$V_{GS} = -10V, I_D = -20A$	
Static Drain-Source On-Resistance	R <sub>DS(ON)</sub>	_	4.9	6.0		$V_{GS} = -5V, I_{D} = -20A$	
Diode Forward Voltage	$V_{SD}$	_	-0.7	-1.2	V	$V_{GS} = 0V, I_{S} = -1A$	
DYNAMIC CHARACTERISTICS (Note 10)							
Input Capacitance	C <sub>iss</sub>	_	3,775	_	рF	451/ 1/ 01/	
Output Capacitance	Coss	_	932	_	рF	$V_{DS} = -15V, V_{GS} = 0V$ - f = 1MHz	
Reverse Transfer Capacitance	C <sub>rss</sub>	_	500	_	рF		
Gate Resistance	$R_g$	_	21	_	Ω	$V_{DS} = 0V$ , $V_{GS} = 0V$ , $f = 1MHz$	
Total Gate Charge	Qg	_	127	_	nC	45)/ )/ 40)/	
Gate-Source Charge	$Q_{gs}$	_	24.5	_	nC	$V_{DS} = -15V, V_{GS} = -10V,$ $I_{D} = -20A$	
Gate-Drain Charge	$Q_{gd}$	_	28.5	_	nC	1D = -20A	
Turn-On Delay Time	t <sub>D(ON)</sub>	_	6.9	_	ns		
Turn-On Rise Time	t <sub>R</sub>	_	4.0	_	ns	$V_{DD} = -15V, V_{GEN} = -10V,$ $R_{GEN} = 3\Omega, I_D = -20A$	
Turn-Off Delay Time	t <sub>D(OFF)</sub>	_	372	_	ns		
Turn-Off Fall Time	t <sub>F</sub>	_	160	_	ns		
Reverse Recovery Time	t <sub>RR</sub>	_	26.5	_	ns	1 200 4:/44 5000/	
Reverse Recovery Charge	Q <sub>RR</sub>	_	37.3	_	nC	$I_F = -20A$ , di/dt = 500A/ $\mu$ s	

5. Device mounted on FR-4 substrate PC board, 2oz copper, with minimum recommended pad layout.

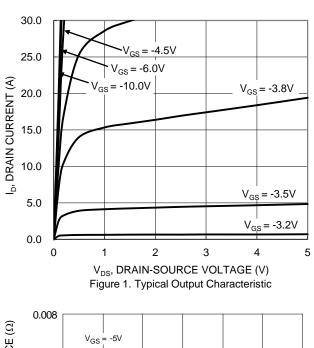
<sup>6.</sup> Device mounted on FR-4 substrate PC board, 2oz copper, with 1inch square copper plate.

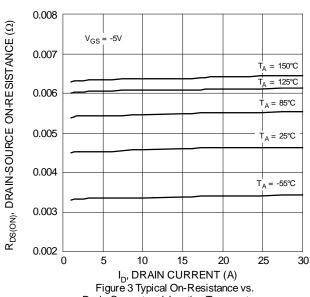
 <sup>7.</sup> Thermal resistance from junction to soldering point (on the exposed drain pad).
 8. I<sub>AS</sub> and E<sub>AS</sub> ratings are based on low frequency and duty cycles to keep T<sub>J</sub> = +25°C.

<sup>9.</sup> Short duration pulse test used to minimize self-heating effect.

<sup>10.</sup> Guaranteed by design. Not subject to product testing.







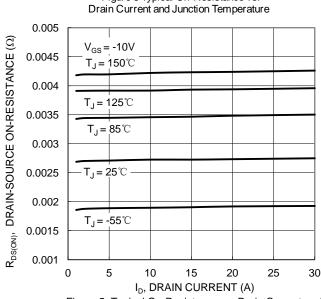
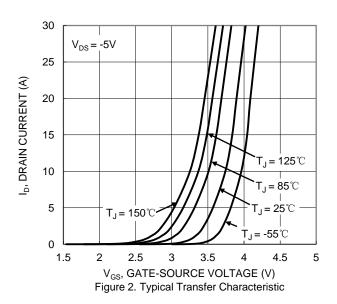


Figure 5. Typical On-Resistance vs. Drain Current and Junction Temperature



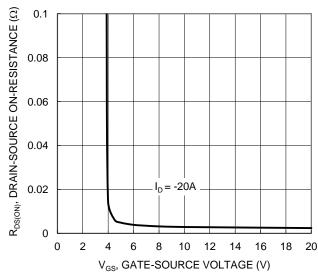


Figure 4. Typical Transfer Characteristic

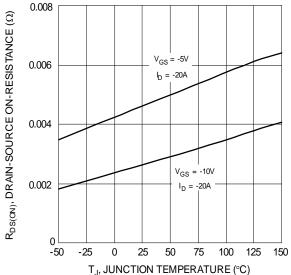


Figure 6 On-Resistance Variation with Junction Temperature





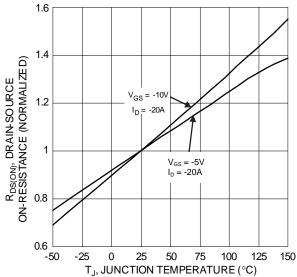
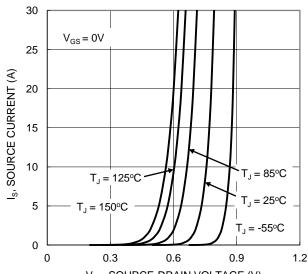
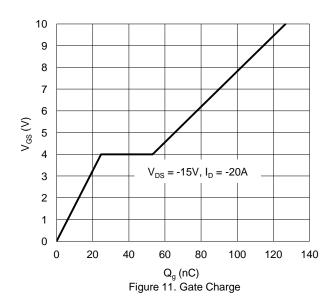


Figure 7 On-Resistance Variation with Junction Temperature

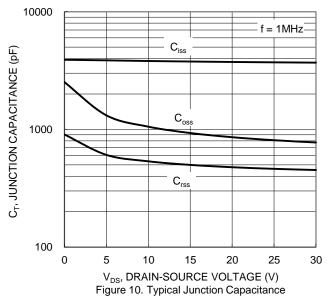


V<sub>SD</sub>, SOURCE-DRAIN VOLTAGE (V) Figure 9. Diode Forward Voltage vs. Current



3  $V_{GS(TH)}$ , GATE THRESHOLD VOLTAGE (V) 2.8 2.6  $I_D = -1mA$ 2.4 2.2  $I_{D} = -250 \mu A$ 2 1.8 1.6 1.4 1.2 1 25 100 -50 50 75 125 150  $T_J$ , JUNCTION TEMPERATURE ( $^{\circ}$ C)

Figure 8. Gate Threshold Variation vs. Junction Temperature



1000  $R_{\text{DS}(\text{ON})}$  Limited 100 DRAIN CURRENT (A) 10  $P_W = 10 ms$ م\_  $T_{J(Max)} = 150$  °C DĊ Single Pulse DUT on Infinite Heatsink  $V_{GS} = -10V$ 0.1 10 0.1 100  $V_{DS}$ , DRAIN-SOURCE VOLTAGE (V) Figure 12. SOA, Safe Operation Area



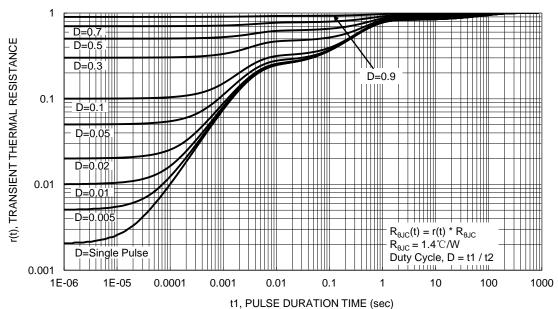


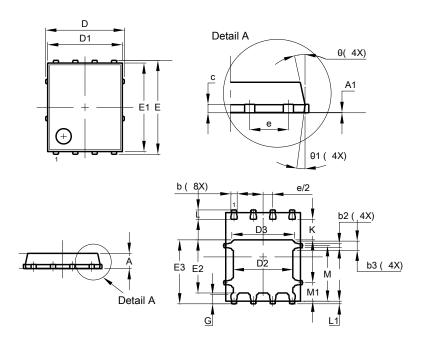
Figure 13. Transient Thermal Resistance



# **Package Outline Dimensions**

Please see http://www.diodes.com/package-outlines.html for the latest version.

#### PowerDI5060-8

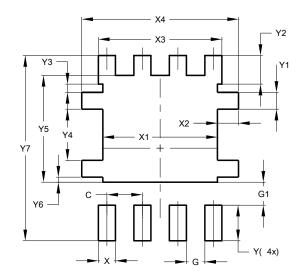


PowerDI5060-8					
Dim	Min	Тур			
Α	0.90	1.10	1.00		
A1	0.00	0.05	-		
b	0.33	0.51	0.41		
b2	0.200	0.350	0.273		
b3	0.40	0.80	0.60		
С	0.230	0.330	0.277		
D		5.15 BSC			
D1	4.70	5.10	4.90		
D2	3.70	4.10	3.90		
D3	3.90	4.30	4.10		
E	(	6.15 BSC			
E1	5.60	6.00	5.80		
E2	3.28	3.68	3.48		
E3	3.99	4.39	4.19		
е	1.27 BSC				
G	0.51	0.71	0.61		
K	0.51	-	-		
L	0.51	0.71	0.61		
L1	0.100	0.200	0.175		
М	3.235	4.035	3.635		
M1	1.00	1.40	1.21		
Θ	10°	12°	11°		
Θ1	6°	8°	7°		
All Dimensions in mm					

# **Suggested Pad Layout**

Please see http://www.diodes.com/package-outlines.html for the latest version.

#### PowerDI5060-8



Dimensions	Value (in mm)
С	1.270
G	0.660
G1	0.820
Χ	0.610
X1	4.100
X2	0.755
Х3	4.420
X4	5.610
Υ	1.270
Y1	0.600
Y2	1.020
Y3	0.295
Y4	1.825
Y5	3.810
Y6	0.180
Y7	6.610



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